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IN THE UNITED STATES PATENT AND TRADEMARK OFFICE	
SUPPLEMENTAL INFORMATION DISCLOSURE STATEMENT	Atty. Docket No. UBAT1490-2



Applicant(s) Gregory R. Hanson et al.	
Application Number 10/607,840	Date Filed June 27, 2003
For FASTER PROCESSING OF MULTIPLE SPATIALLY- HETERODYNED DIRECT-TO-DIGITAL HOLOGRAMS	
Group Art Unit 2877	Examiner
Confirmation Number: 8468	

Mail Stop Amendment
Commissioner for Patents
PO Box 1450
Alexandria, VA 22313-1450

Dear Sir:

<p align="center"><u>Certificate of Mailing Under 37 C.F.R. 1.8</u></p> <p>I hereby certify that this correspondence is being deposited with the United States Postal Service as First Class Mail in an envelope addressed to: Commissioner for Patents, P.O. Box 1450, Alexandria, VA 22313 on <u>Aug 24</u>, 2005.</p> <p align="center"> John J. Bruckner</p>

Applicant respectfully requests, pursuant to 37 C.F.R. §§ 1.56, 1.97 and 1.98, that the reference(s) listed on the attached PTO/SB/08A and/or PTO/SB/08B forms be considered and cited in the examination of the above-identified application. Pursuant to 37 C.F.R. §§ 1.97(g) and (h), no representation is made that a search has been made or that this art is material to the patentability of the present application. Copies of the non-US references are enclosed for the convenience of the Examiner.

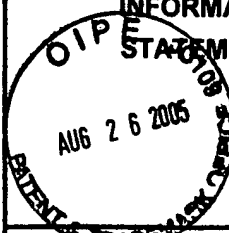
While Applicants believe no (further) fees are due, if any (further) fees are due, the Commissioner is hereby authorized to charge any fees or credit any overpayments to Deposit Account No. 50-3204 of John Bruckner PC.

Dated: Aug 24, 2005

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Respectfully submitted,
John Bruckner PC

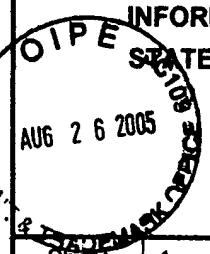
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 INFORMATION DISCLOSURE STATEMENT BY APPLICANT		Application Number	10/607,840
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		First Named Inventor	Gregory R. Hanson
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		Examiner Name	
Sheet 1 of 1	Attorney Docket	UBAT1490-2	

U.S. PATENT DOCUMENTS

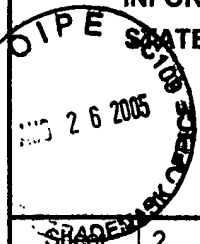
Examiner Initials	Cite No.	Document Number		Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document
		Number	Kind Code (if known)		
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		20040130762		07/08/2004	Thomas et al.

Examiner Initials	Cite No.	FOREIGN PATENT DOCUMENTS			Publication Date MM-DD-YYYY (Number 43)	Name of Patentee or Applicant of Cited Document
		Country Code	Number	Kind Code (if known)		
		JP	06282213		07/10/1994	Citizen Watch Co. Ltd.
Examiner Signature					Date Considered	

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